

Notice of References Cited

Application/Control No.

09/784,340

Applicant(s)/Patent Under

Reexamination

WEI ET AL.

Examiner

Delia M. Ramirez

Art Unit

1652

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U.S. PATENT DOCUMENTS

* *		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-60197590	04-2000	Policky et al.	536/23.2
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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